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(57) Abstract:

Method and System for Major Event Detection in a Power System ABSTRACT According to an aspect of the present invention, a system for detecting the major event in an electric power supply network comprising, a plurality of phasor measurement units (PMU) (110 A-M) configured to senses several electrical parameters and generate the data representing the sensed electrical parameters, an abnormality detector (130) configured to dynamically detect the abnormality in the data, and a fault detector 140 configured to detects the fault and the fault location based on the abnormality detected. In particular, the abnormality detector (130) operative to generate weighted abnormality probability densities indicative of the region of high probability of events and the fault detector 140 operative apply threshold values to the weighted abnormality probability densities to identify the fault.

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